

Design and implementation of Gigabit $0.25\mu\text{m}$ CMOS Transimpedance amplifier(TIA) for Optical Receiver Application

Jae seo Lee

2001. 12. 19

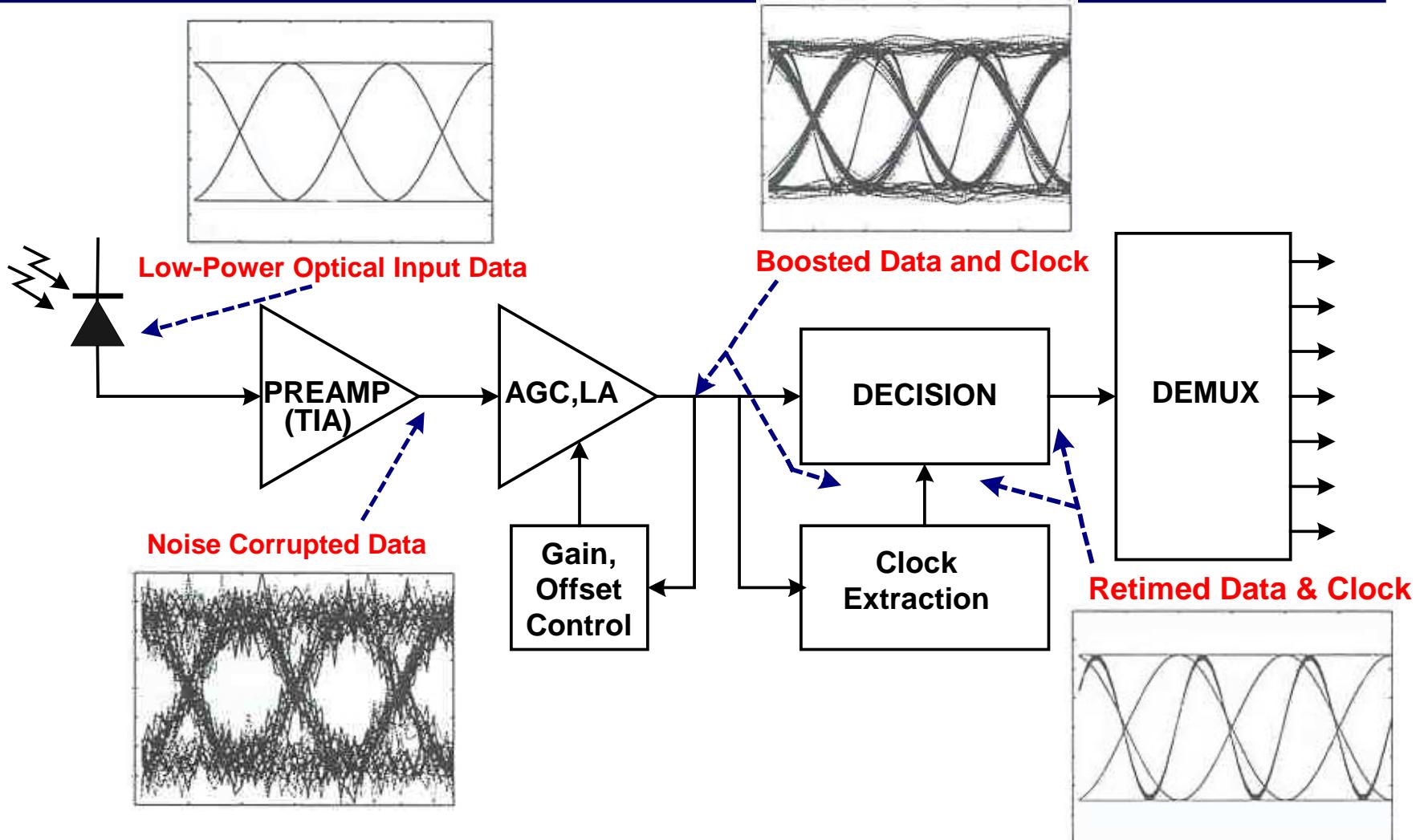
Semiconductor System Laboratory

**Department of Electrical Engineering and Computer Science
Korea Advanced Institute of Science and Technology (KAIST)**

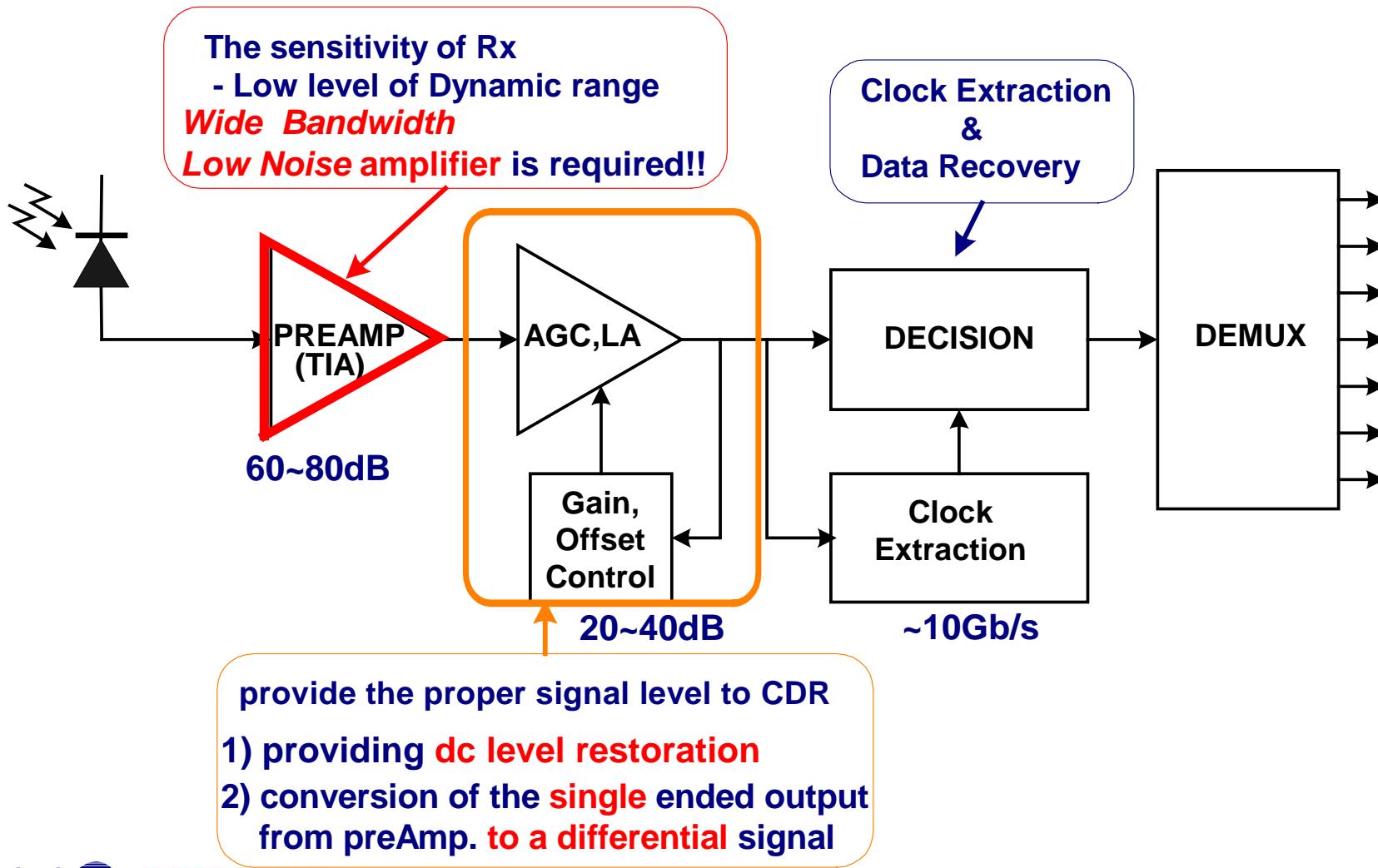
Outline

- Motivation
 - Overview of optical receiver
 - Design goal
- Transimpedance Amplifier (TIA)
- Conventional Approaches
- Proposed Approaches
- Measurement results
- Conclusions

What is Optical Receiver?



Overview of Optical Rx Design



Design Goal

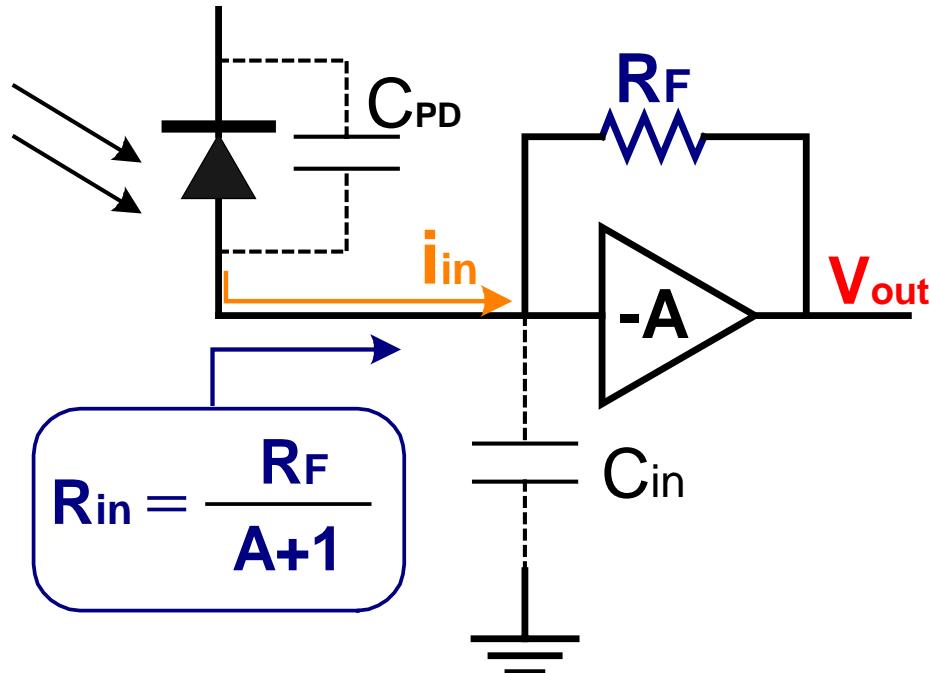
- Gain range : 60~80dB ($1\text{k}\Omega \sim 10\text{k}\Omega$)
- Wide bandwidth
- Low Noise
- Fully Differential Preamplifier
- CMOS implementation

Outline

- Motivation
- Transimpedance Amplifier (TIA)
 - Why TIA?
 - Noise Source
 - TIA Noise & Design Solution
- Conventional Approaches
- Proposed Approaches
- Measurement results
- Conclusions

Why Transimpedance amp.?

- Transimpedance front-end



$$Z_T(s) = R_T \frac{1}{1+sT}$$

$$R_T = \frac{A}{A+1} R_F$$

$$BW = \frac{1}{2\pi} \frac{A+1}{R_F C_T}$$

$$C_T = C_{PD} + C_{in}$$

Noise Source (1/5)

- Shot Noise
- Thermal Noise
- Frequency Dependent Noise
- Digital noise through same substrate

Noise Source (2/5)

- **Shot noise**
 - Due to the random variations
 - The ultimate limiting factor
 - Power spectral density :
$$S_{shot}(f) = 2qI \quad [A^2 / Hz]$$
 - Rms noise current :
$$i_{rms} = \sqrt{2qI \cdot BW} = \sqrt{2qI / \tau_{BW}}$$

Noise Source (3/5)

- **Thermal Noise**

- Due to the kinetic energy of charged particles
 - Power spectral density :

$$S_{thermal}(f) = \frac{4kT}{R} \quad [A^2 / Hz]$$

- noise current :

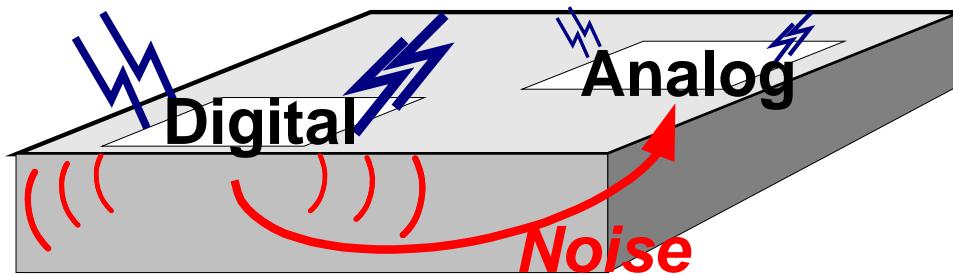
$$i_n^2 = \frac{4kT}{R}$$

Noise Source (4/5)

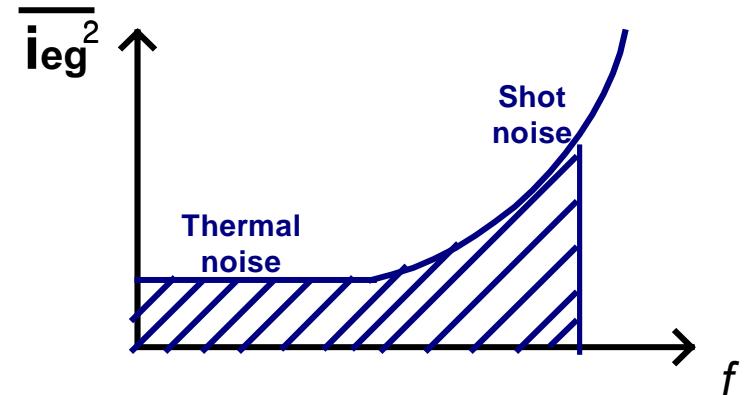
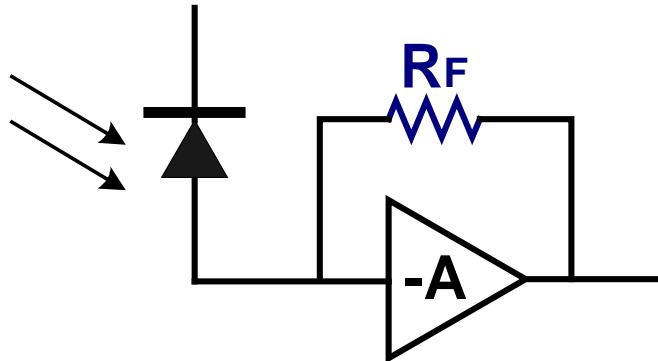
- **Frequency Dependent Noise**
 - Flicker noise (1/f noise)
 - dependent upon the choice of materials, the processing purity
 - @ $f=f_{\text{corner}}$:
Flicker noise = White noise in the device
 - Negligible with the broadband receivers.

Noise Source (4/5)

- **Digital noise**
 - Through same substrate of System On Chip
 - Switching noise
 - Signal induced noise



TIA Noise & Design Solution



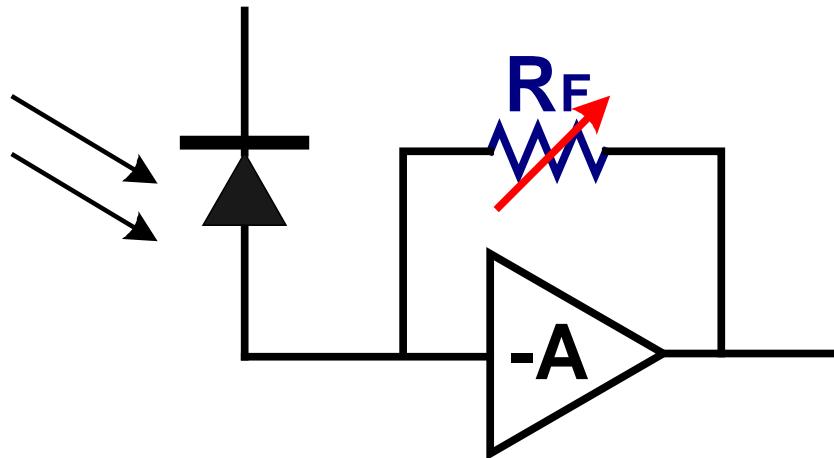
$$\begin{aligned}
 S_{nf}(f) &= \frac{4kT}{R_F} + \left[2qI + \frac{4kT}{R_{in}} \right] \left(\frac{2\pi f C_T}{g_m} \right)^2 \\
 &= \frac{4kT}{R_F} + \frac{w^2 C_T^2}{g_m} \left[\frac{4kT}{R_{in}} + 2qI \right]
 \end{aligned}$$

- **Increase g_m , R_{in} , Decrease C_T !!**

Outline

- Motivation
- Transimpedance Amplifier (TIA)
- Conventional Approaches
 - Wide dynamic techniques
 - Wide bandwidth techniques
 - Shunt peaking
 - Common gate input stage
- Proposed Approaches
- Measurement results
- Conclusions

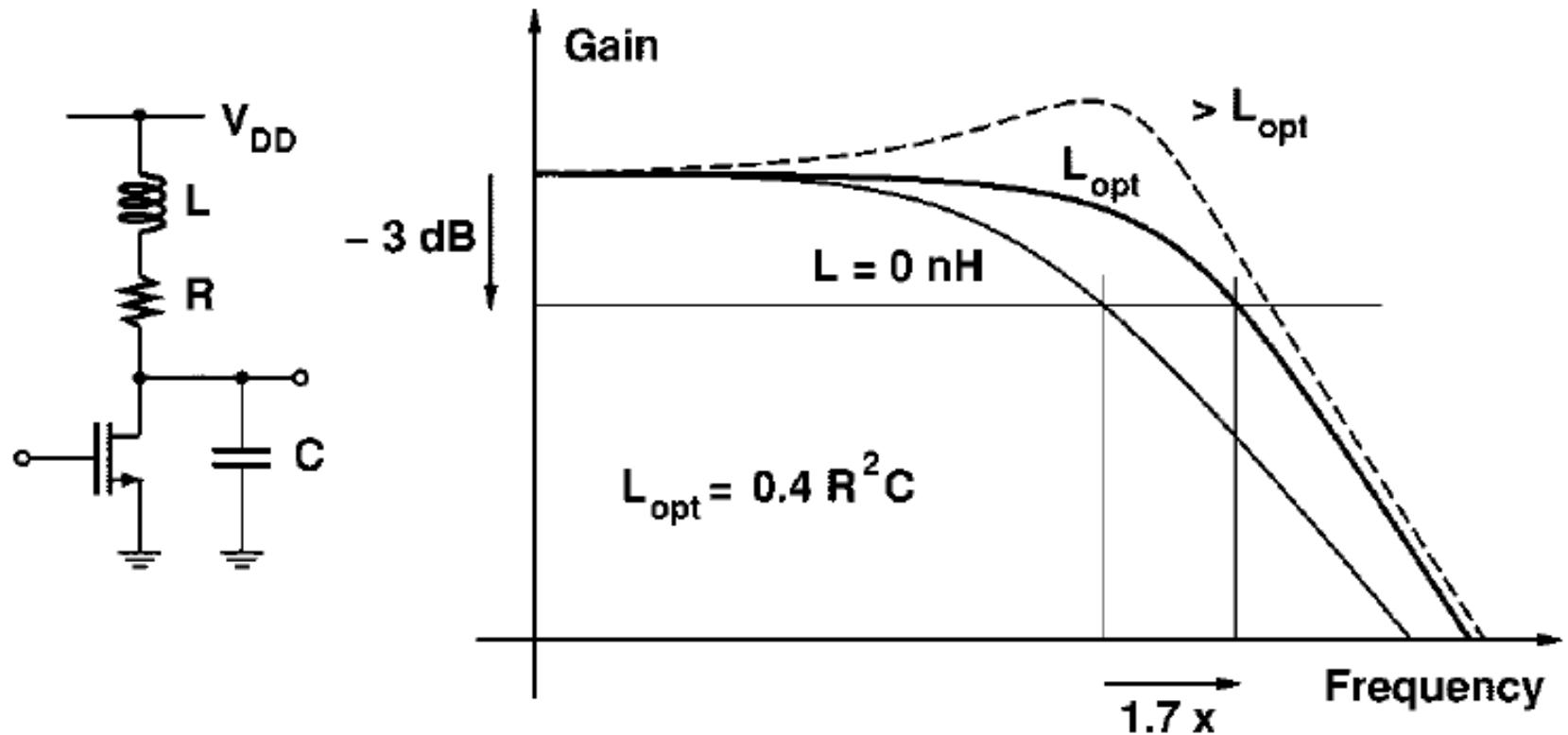
Wide dynamic range technique



- **Adaptive Transimpedance**
 - Increased dynamic range
 - H. Khorramabadi ISSCC'95
 - A 1.06Gb/s, -31dBm to 0dBm BiCMOS optical preamplifier featuring adaptive transimpedance
 - K. Phang ISSCC'01
 - A 1V 1mW CMOS Front-End with On-Chip Dynamic Gate Biasing for a 75Mb/s Optical Receiver

Wide bandwidth techniques(1/3)

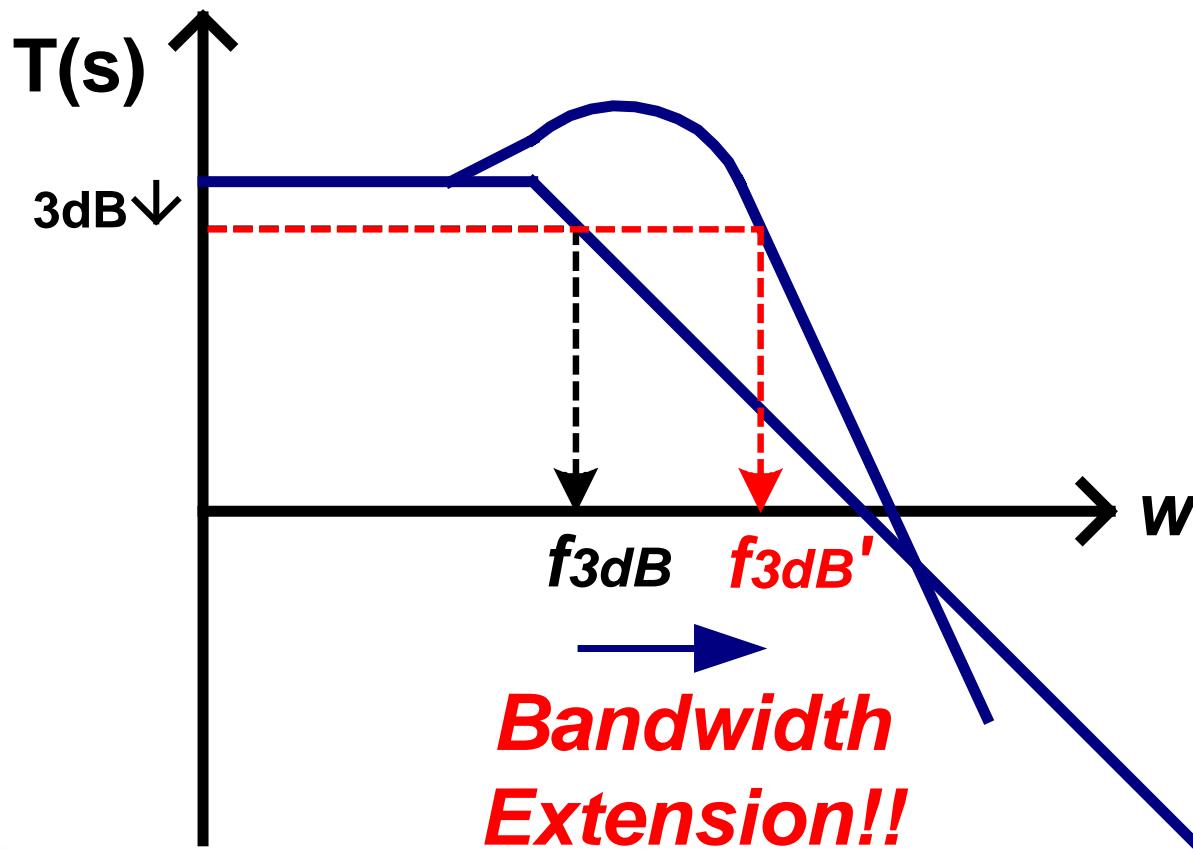
- Shunt peaking



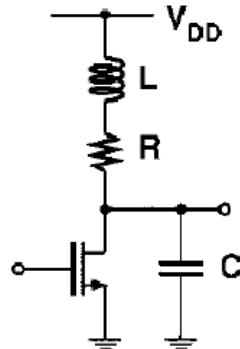
Wide bandwidth techniques(2/3)

- Shunt peaking

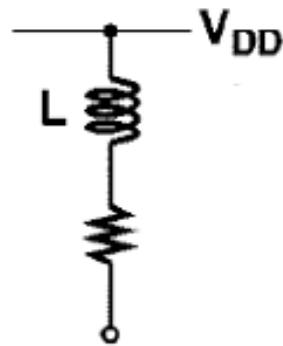
- Add zero



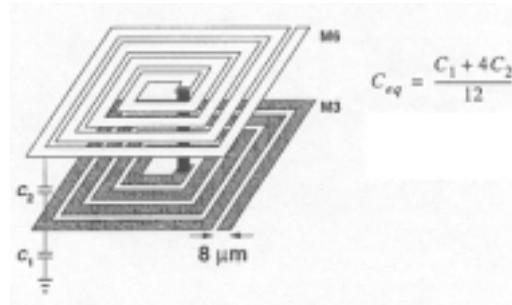
Wide bandwidth techniques(3/3)



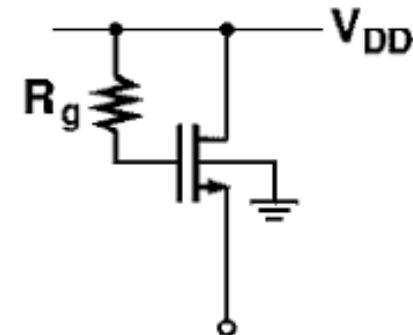
- L-implementation :
 - (a) Spiral inductors
 - (b) Active inductors



(a)



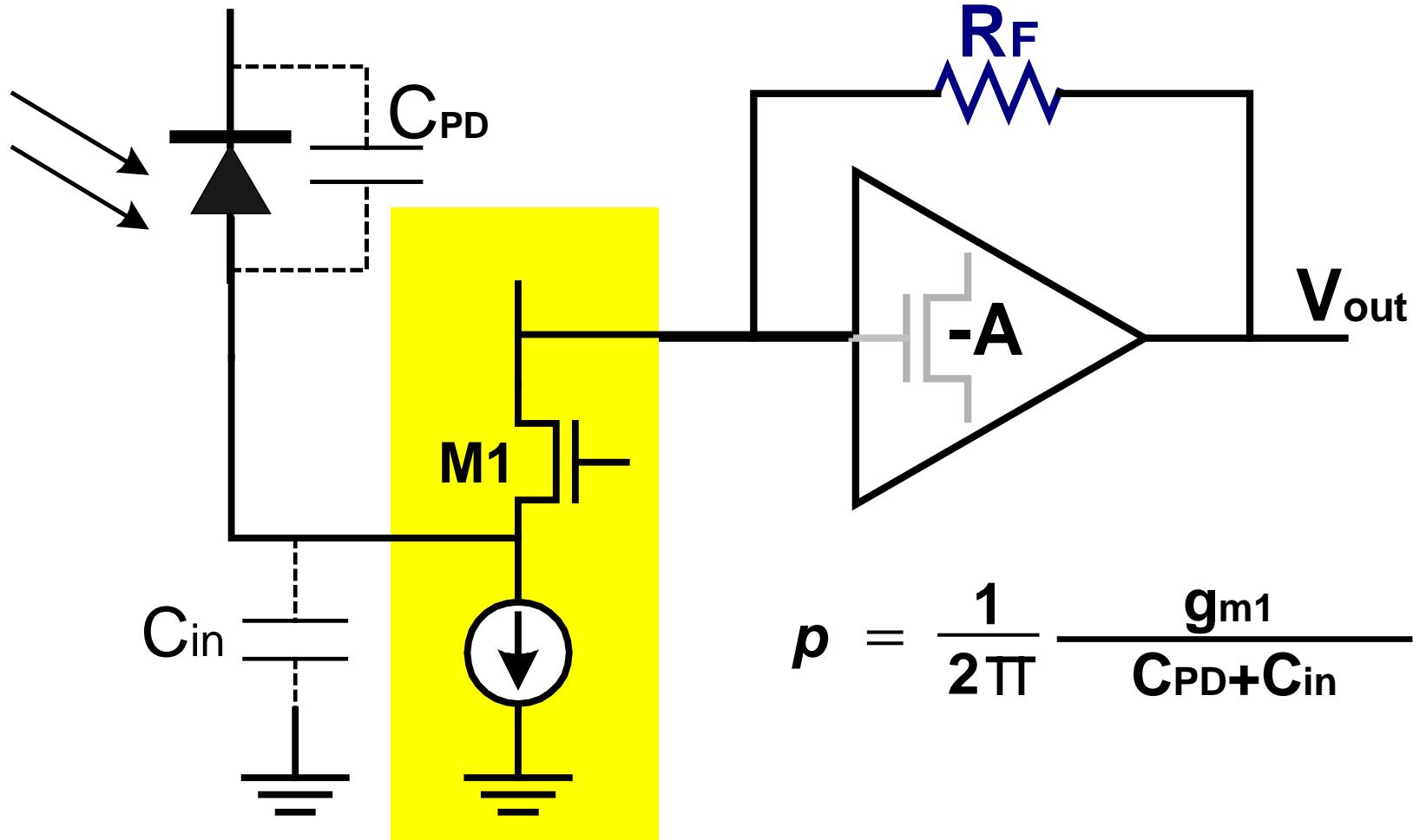
$$L = \frac{R_g}{\omega_T}$$



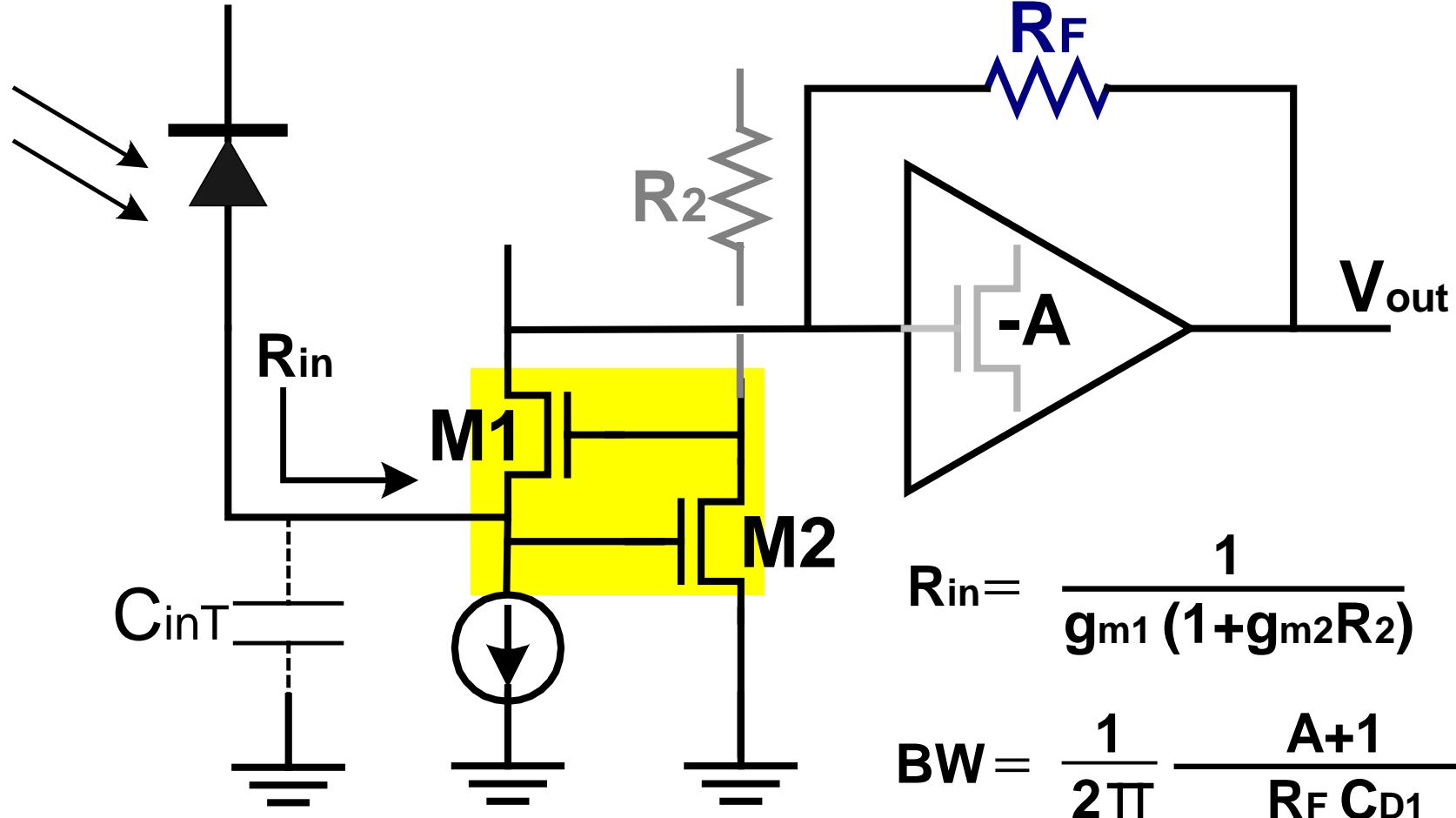
(b)

- (a) J. Savoj et al., “A 10Gb/s CMOS Clock and Data Recovery Circuit with Frequency Detection”, ISSCC’01
- (b) E. Säckinger et al., “A 3-GHz 32-dB CMOS Limiting Amplifier for SONET OC- Receivers” ISSCC’00

Common-Gate Input stage



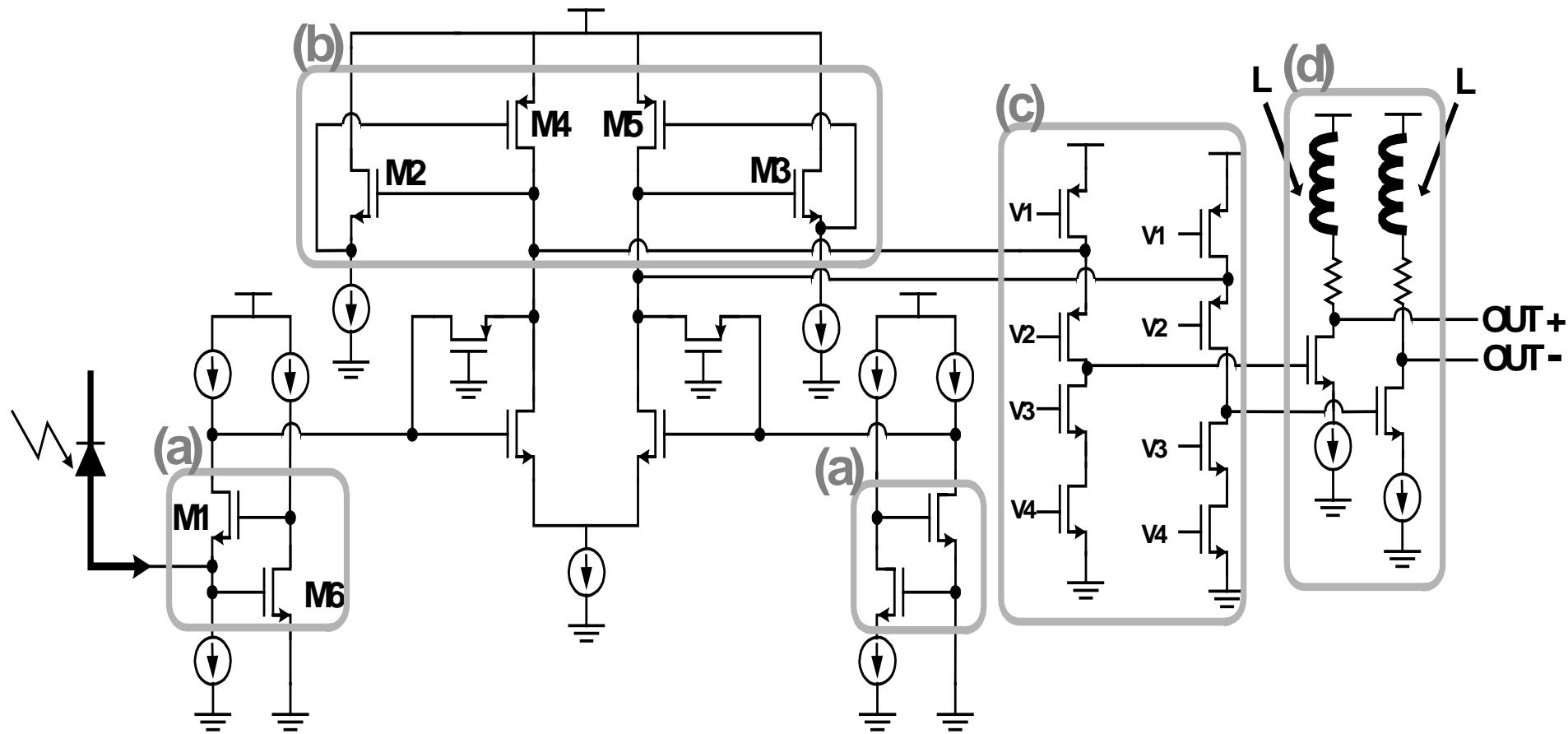
Regulated-Cascode Input stage



Outline

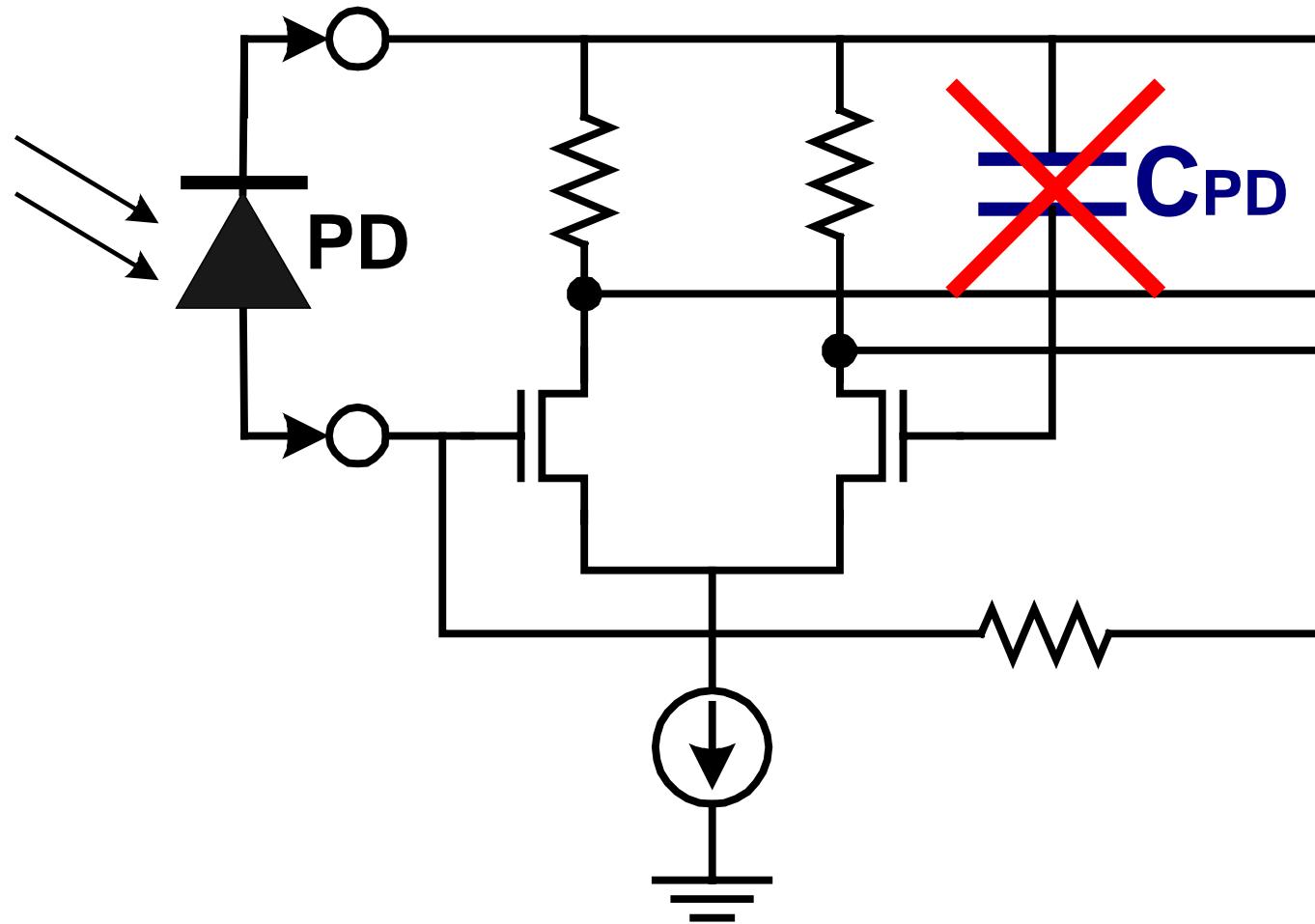
- Motivation
- Transimpedance Amplifier (TIA)
- Conventional Approaches
- **Proposed Approaches**
- Measurement results
- Conclusions

Proposed Structure(1/3)



Proposed Structure(2/3)

- Fully Differential configuration
- Regulated Cascode input stage
 - No need of the matching capacitor at the differential input stage due to PD
 - Bandwidth Enhancement Technique
- Wide swing technique
 - Conventional loads are replaced with V_{th} compensation loads.



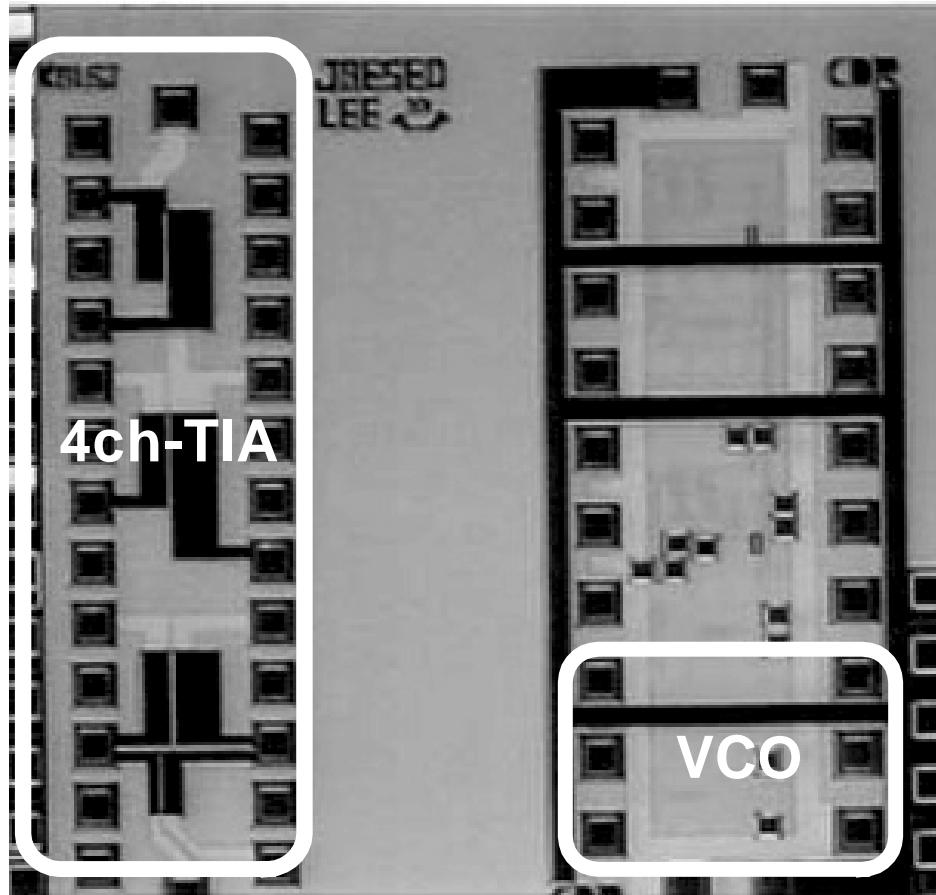
Proposed Structure(3/3)

- Shunt peaking technique
- Low Noise technique
 - Regulated Cascode:
 - Increasing g_m which makes low noise characteristic
 - Substrate Bias Effects on the drain current
- Buffer replaced with cascoded stage
 - Amplifier ability ($\sim 20\text{dB}\Omega$ differential) with DC level shifting
 - Low power consumption with high gain characteristic

Outline

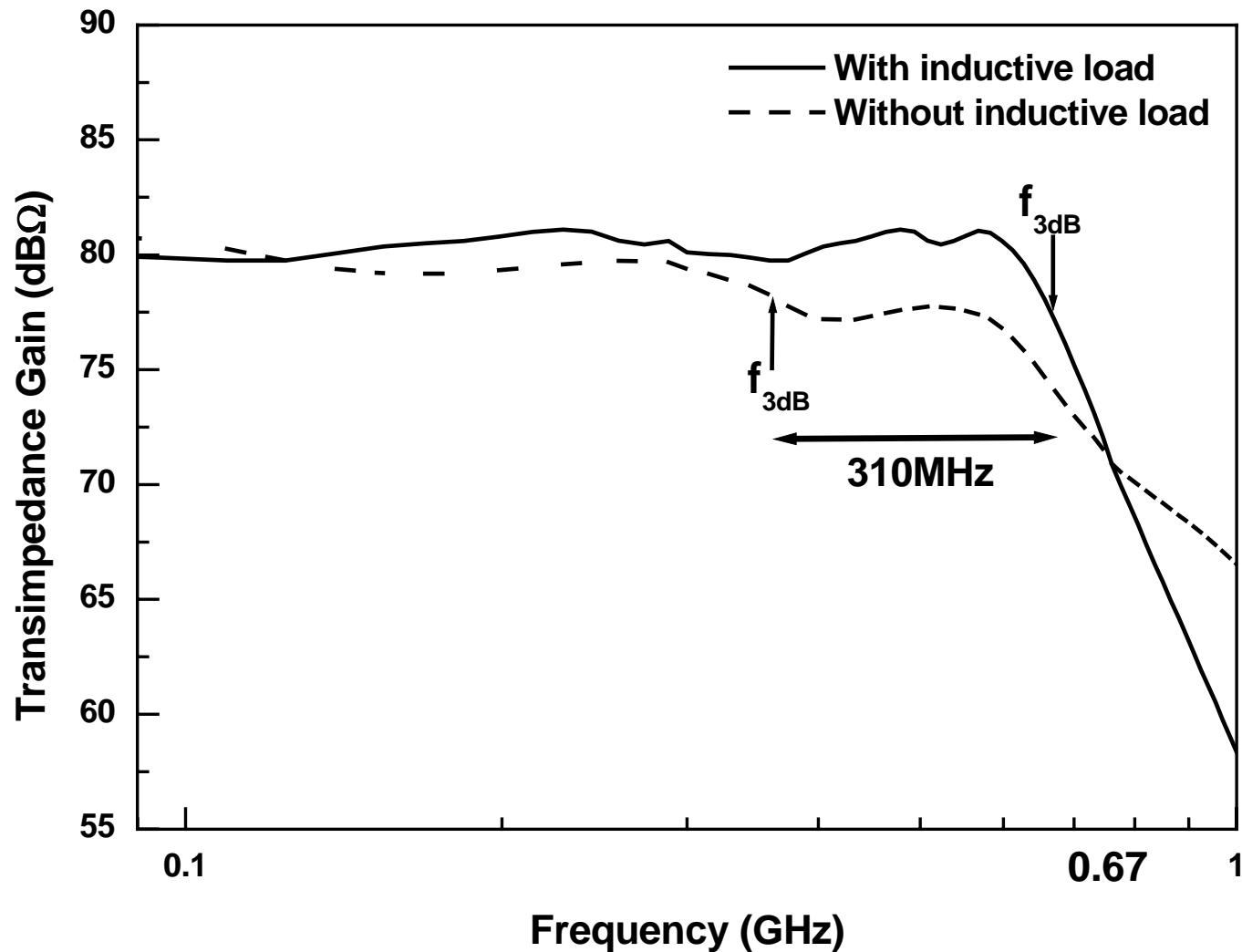
- Motivation
- Transimpedance Amplifier (TIA)
- Conventional Approaches
- Proposed Approaches
- **Measurement results**
 - Chip Microphotograph
 - Gain, Bandwidth, Crosstalk & Noise current
 - Digital Noise
 - Multichip Oxide Process Chip
 - Test boards
 - Eye diagrams
- Conclusions

Chip microphotograph

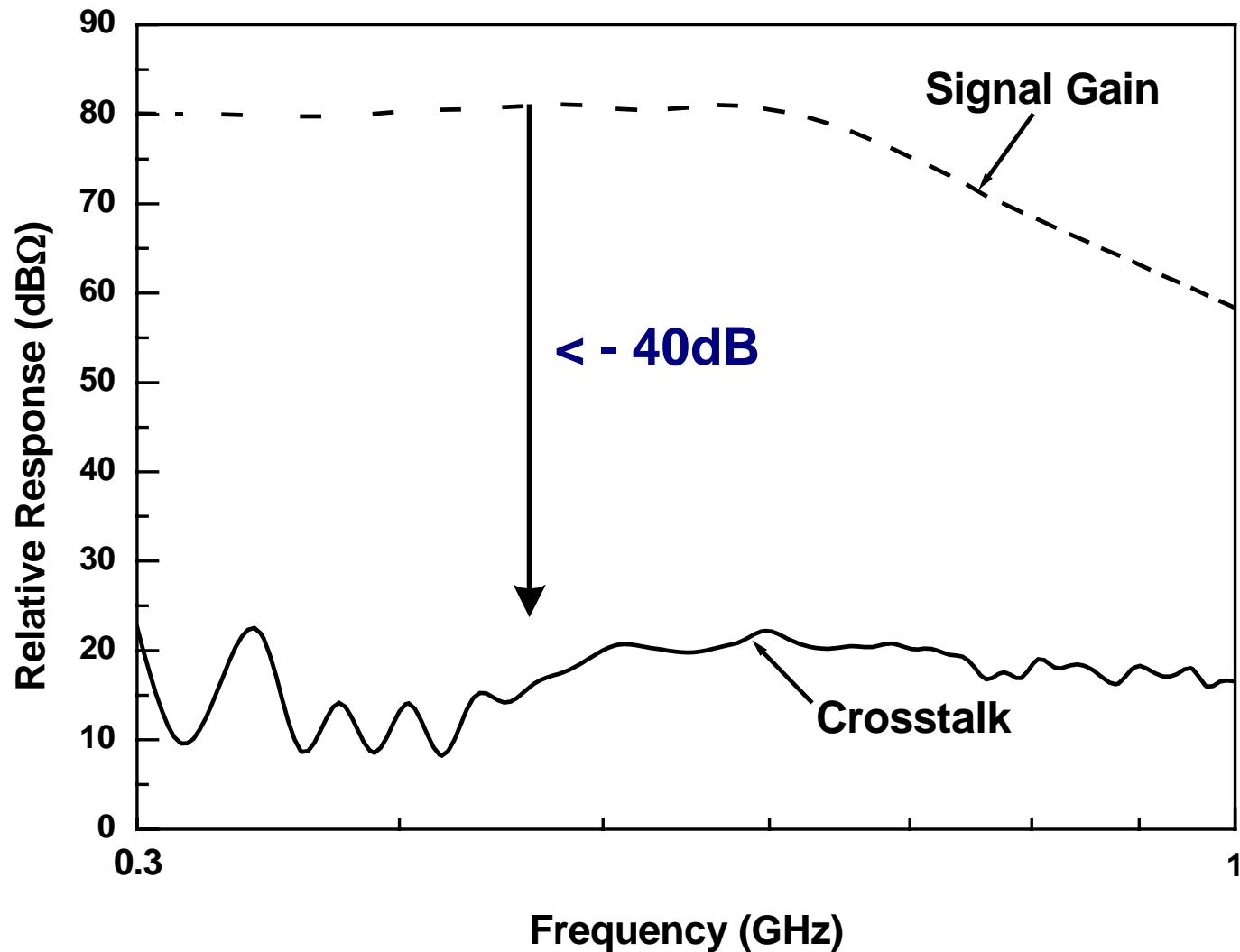


- 0.25 μ m Standard CMOS
- 1poly 5metal
- Retrograde twin well
- 2mm x 2mm

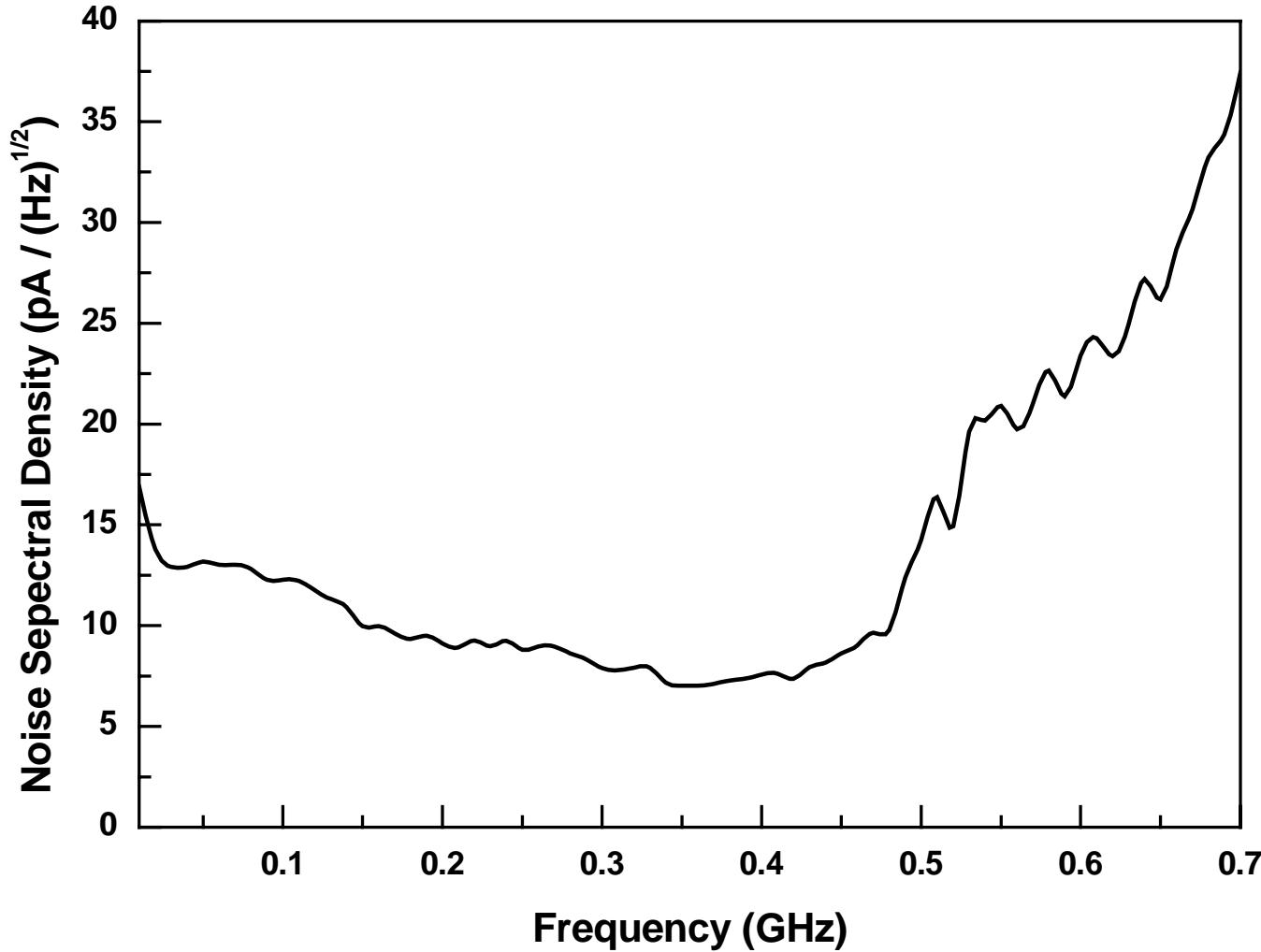
Gain & Bandwidth



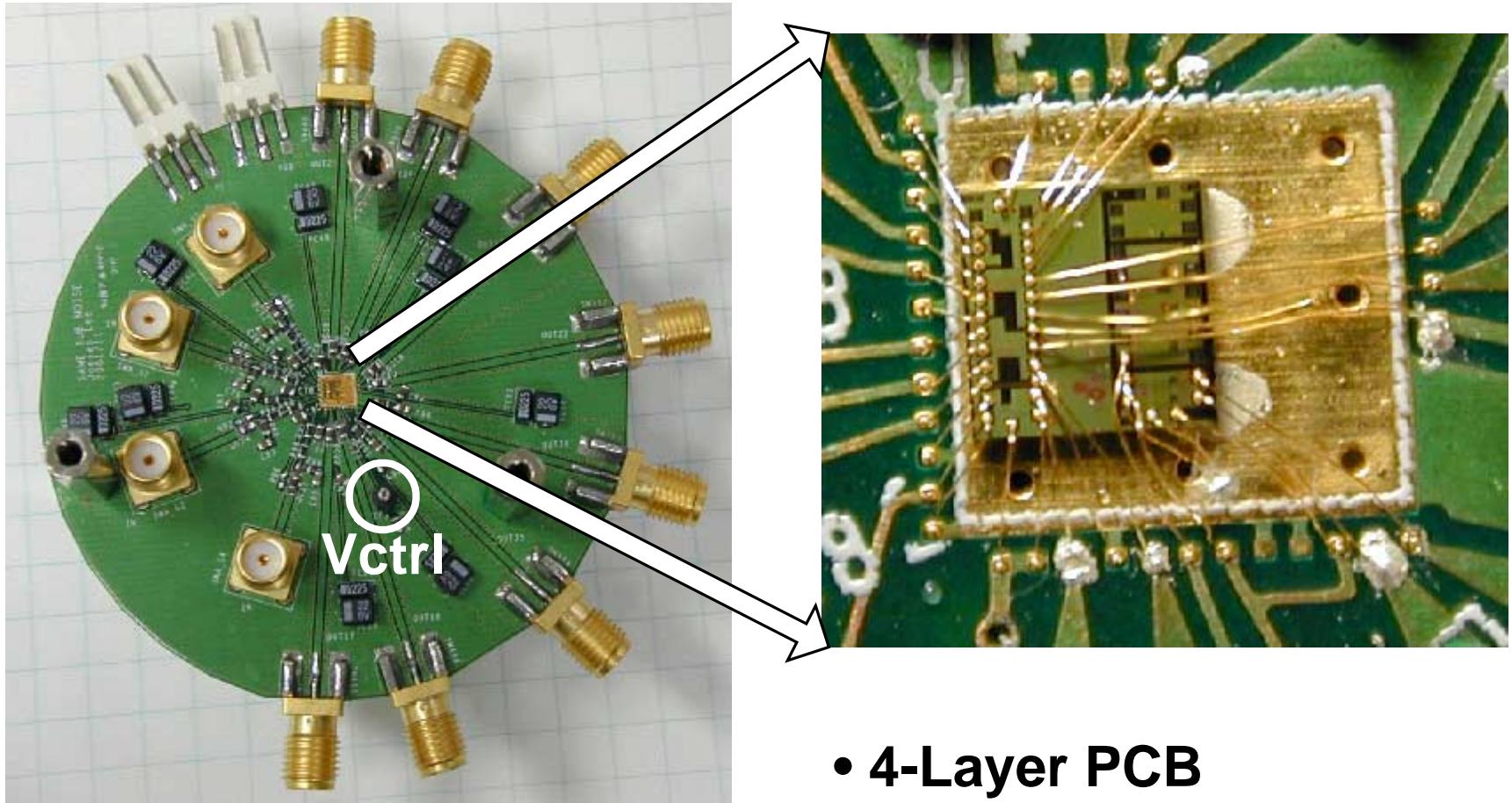
Crosstalk



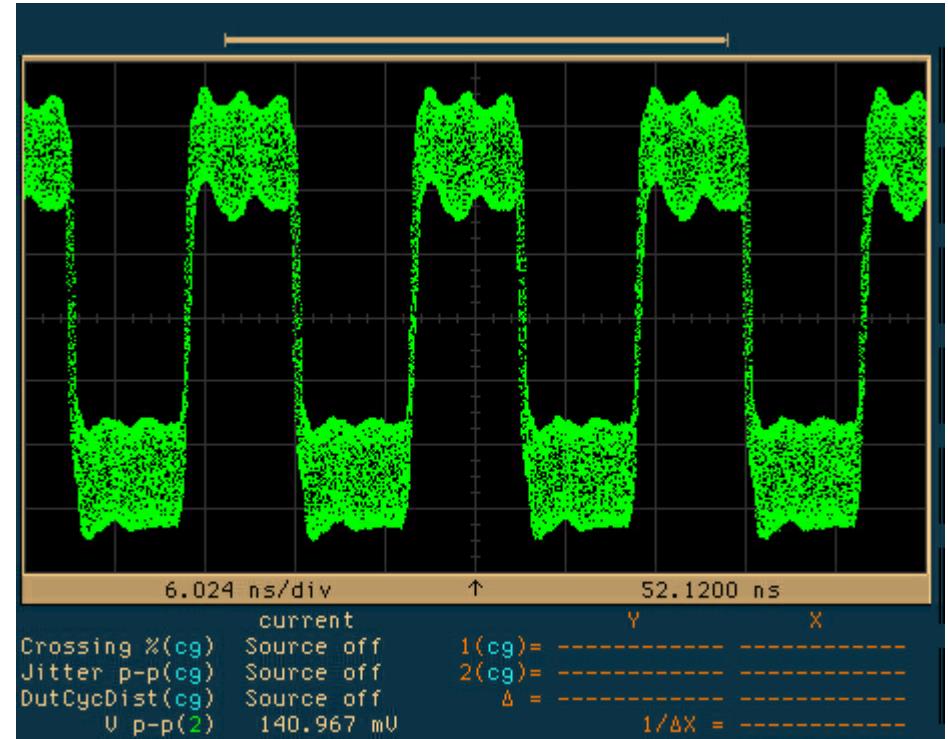
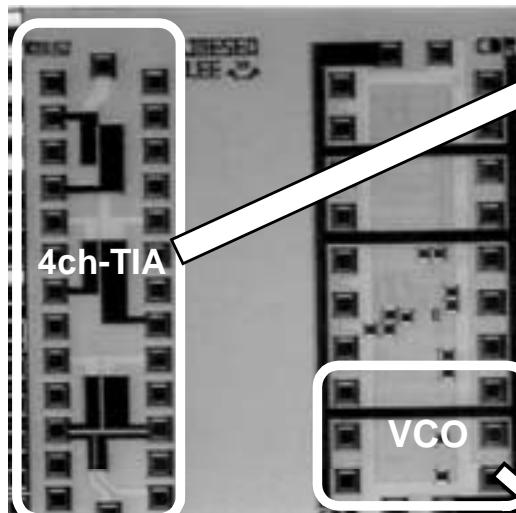
Noise Current



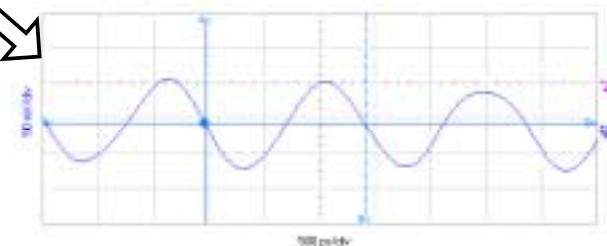
Digital noise test board



Digital noise through same substrate

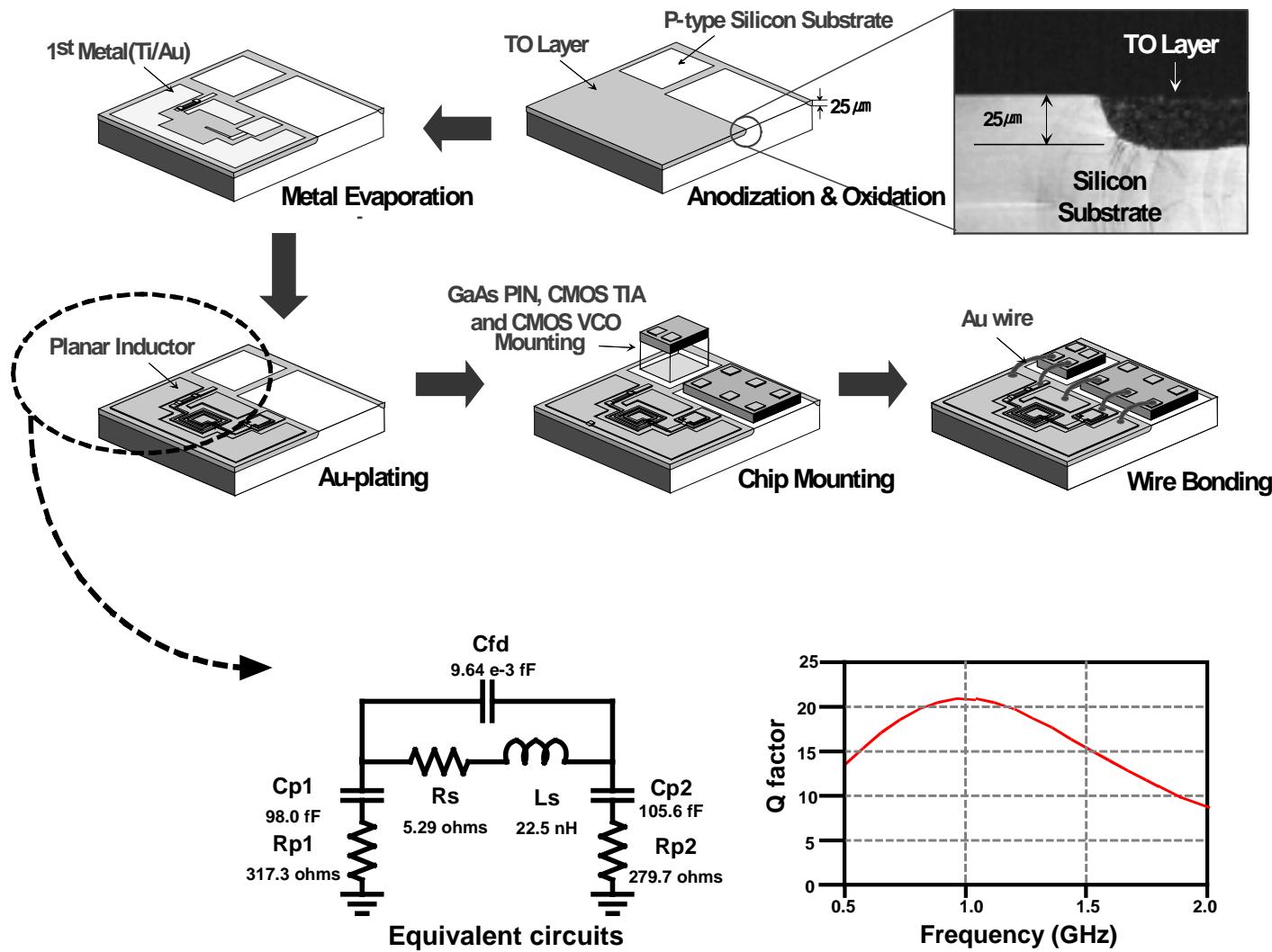


Process:
Retrograde twin well

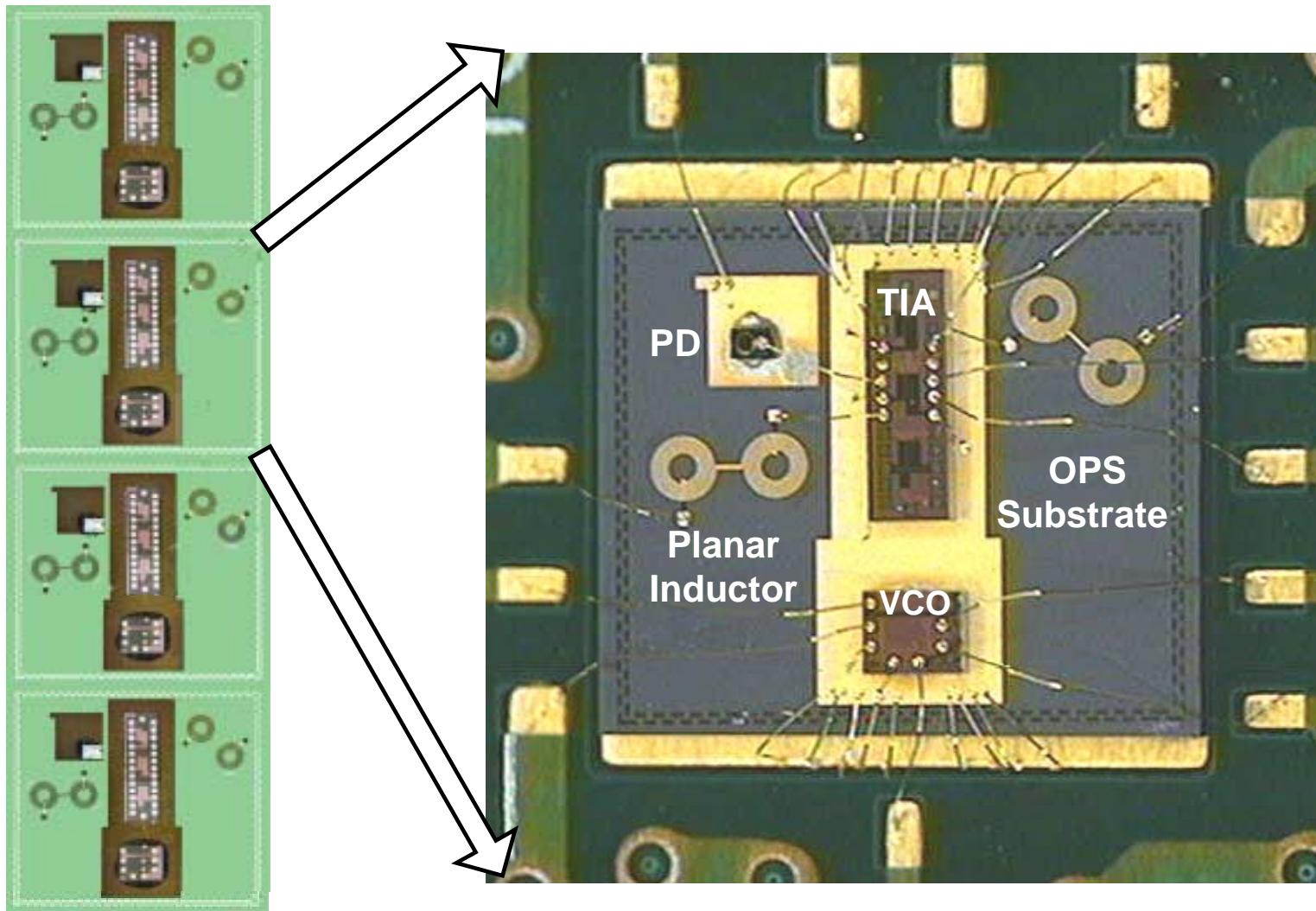


Output at $V_{ctrl}=1.2V$

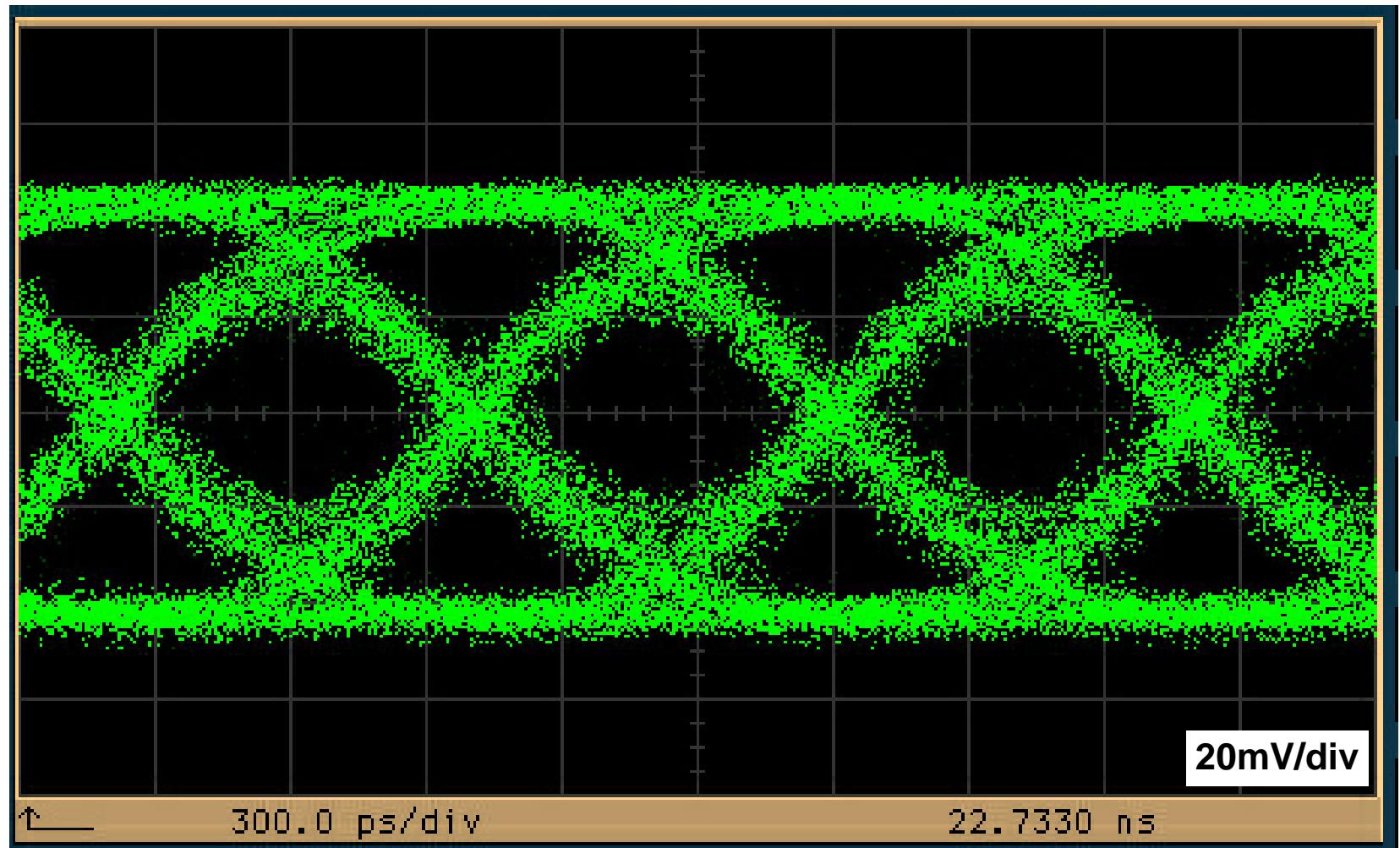
Multichip on Oxide (MCO) Process



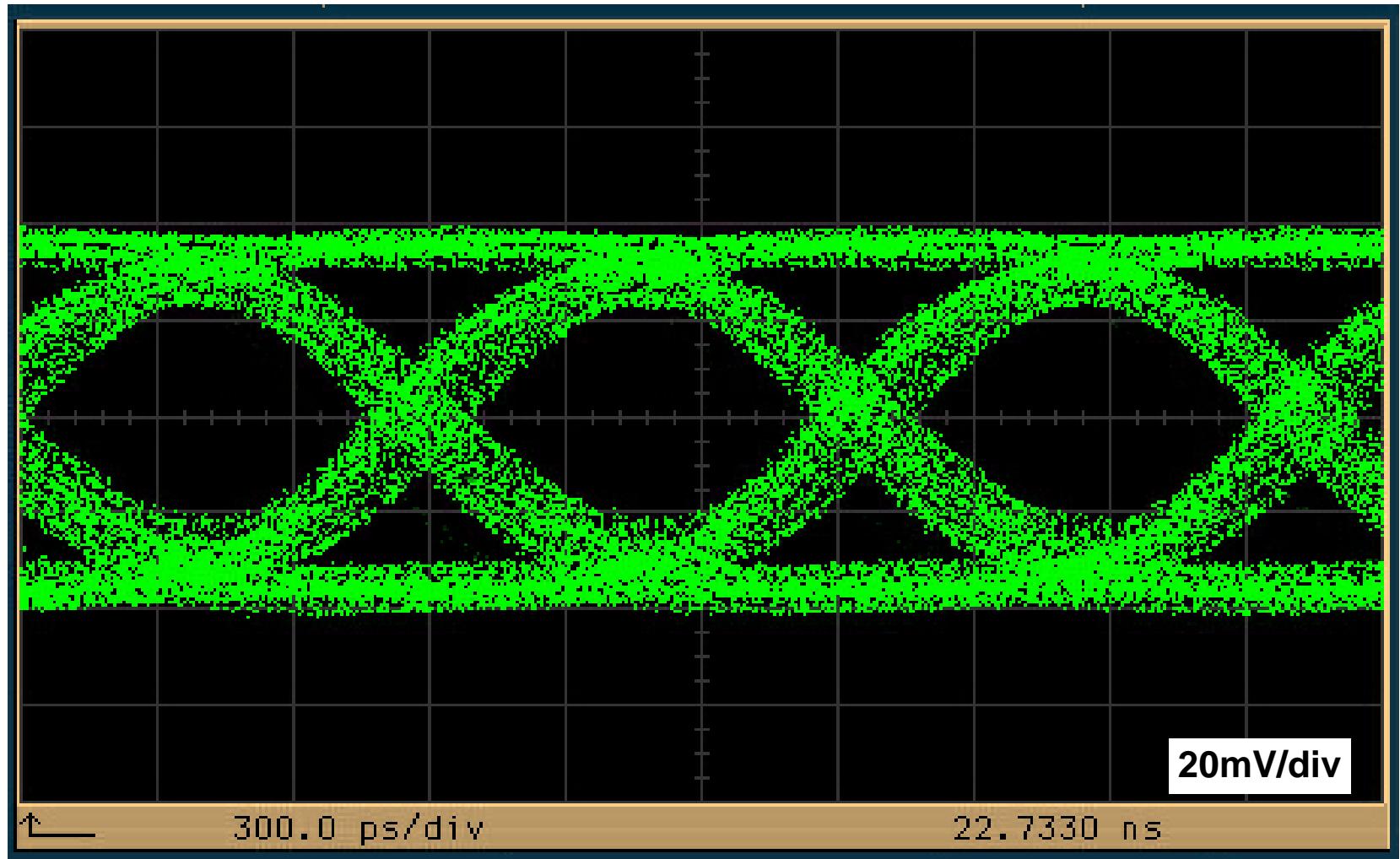
MCO Chip microphotograph



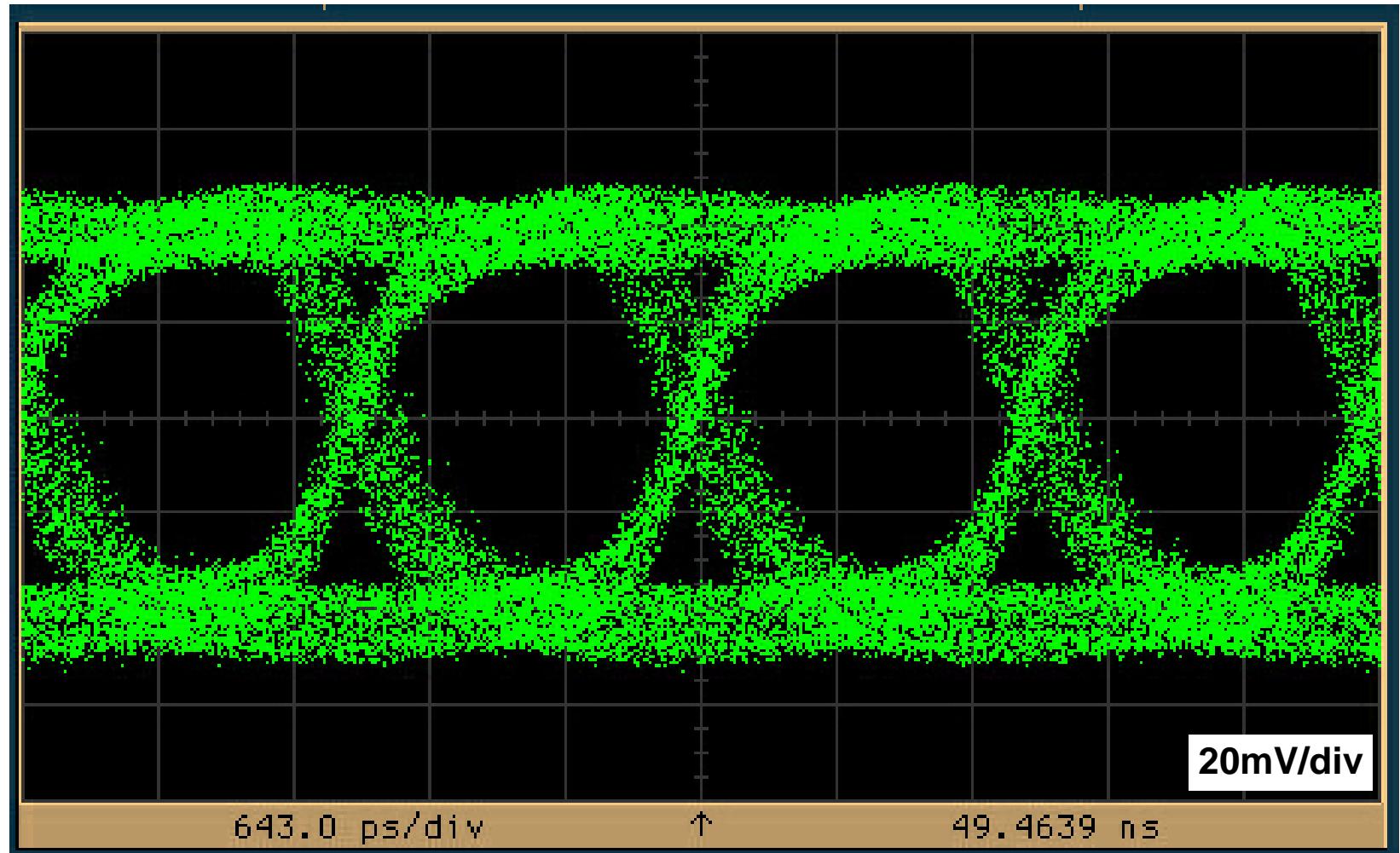
Eye-diagram – 1.25Gbps



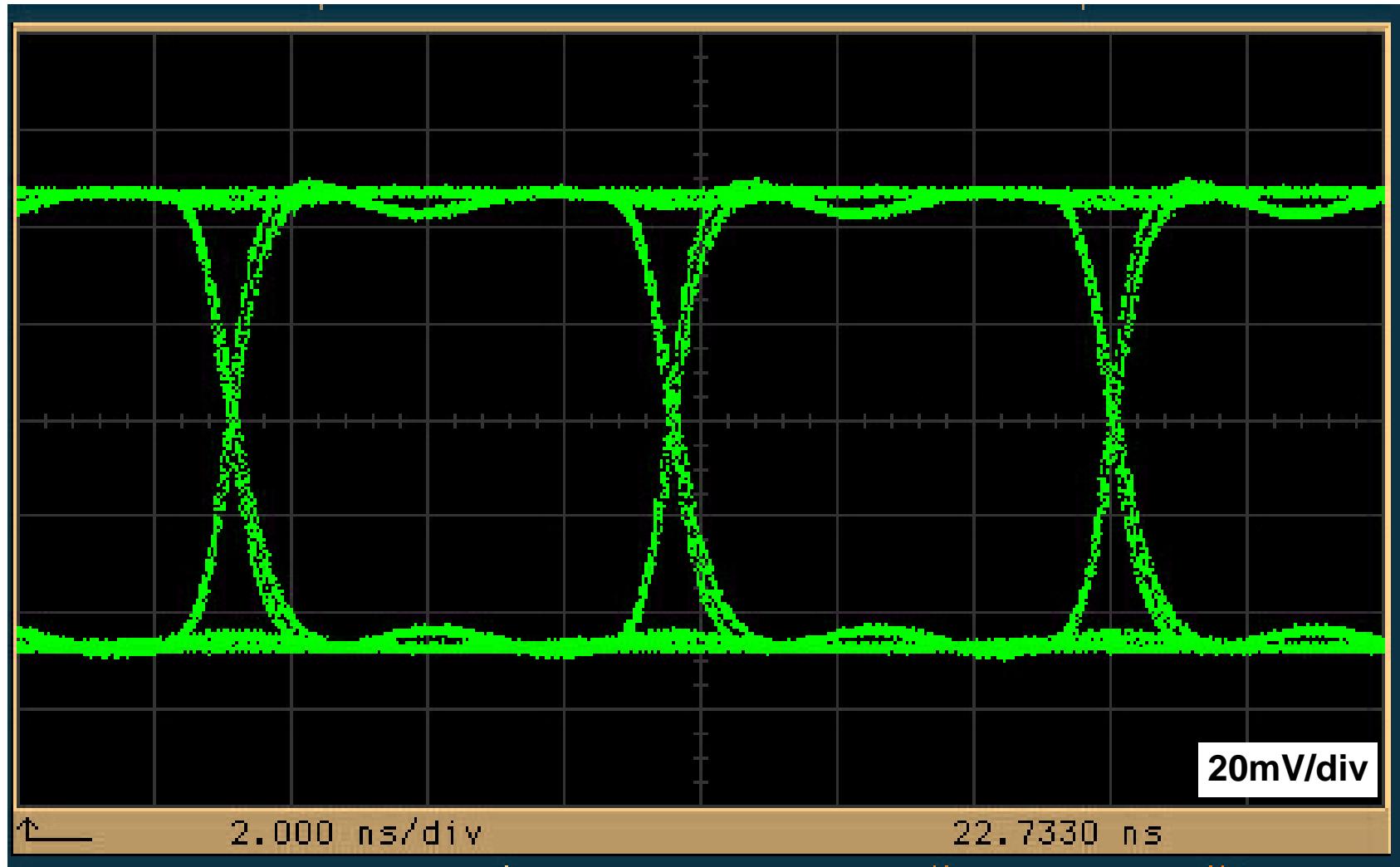
Eye-diagram – 1.022Gbps



Eye-diagram – 622Mbps



Eye-diagram – 155Mbps



Performance summary

Supply voltage	2.5V
Power consumption	27mW
Bandwidth(3dB)	670MHz
Photodiode capacitance	1pF
Noise current	0.13μA
Transimpedance Gain	80dBΩ (differential) 74dBΩ (single-ended)
Max output voltage swing (single-ended)	200 mVp-p
Die area	0.13 x 0.16 mm ² (active area of TIA) 5 x 5 mm ² (MCM chip)
Technology	0.25μm standard CMOS

Conclusion

- Approach to One-chip Solution for Optical Receiver with Digital Noise Free
- Design and implementation of gigabit 0.25mm CMOS transimpedance amplifier for optical receiver application
- Verification through measurements